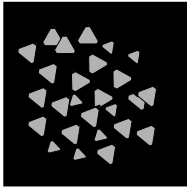


Photographic Emulsions

■ More difficult to quantify



- Light-sensitive "grains" of silver halide in the emulsion
- Placed "randomly" in emulsion
- "Random" sizes
- "large" grains are more sensitive (respond to few photons)
- "small" grains produce better resolution

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Sensors with "Pixels"

■ Regularly spaced "grid" of sensing elements

- Different from random character inherent in emulsions
- Easy to "characterize" the sensitivity and to compensate

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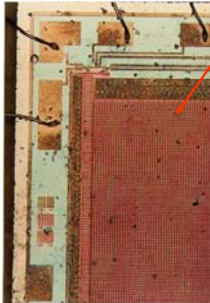
Charge-Coupled Devices (CCDs)

- Standard light detection medium in digital cameras
 - Price has decreased significantly
- Advantages over photochemical emulsions:
 - Most incident photons are "counted" (i.e., have a detectable effect on sensor)
 - ▶ *Quantum Efficiency (QE)* is "large" (may be 80%)
 - *Linear Response*
 - ▶ Measured signal proportional to number of incident photons
 - Fast processing (CCD readout speeds ≈ 1 sec)
 - ▶ NO development of emulsion!
 - Regular grid of sensor elements (pixels)
 - ▶ vs. random distribution of AgX grains
 - Image delivered in computer-ready form

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Charge-Coupled Device = CCD



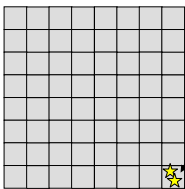
- Individual Sensors
 - "Picture Elements" = Pixels
- Convert photons to electrons
- Pixel Size \Rightarrow Image "Resolution"
- Area of Pixels \Rightarrow "coverage" or "field of view"
- Sensitive over wide range of wavelengths ("colors")
 - from Ultraviolet to Infrared
 - $350 \text{ nm} \leq \lambda \leq 1000 \text{ nm}$
- Pixels are "read out" in sequence
 - cannot be randomly accessed!!

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Sensor Resolution

- Obvious for Electronic Sensors (e.g., CCDs)



- Elements (pixels) have finite size \Rightarrow limited "resolution"
- Light summed over sensor area
 - "integrated" signal

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What is a CCD?

- "CCD" = "Charge-Coupled Device"
- Invented in 1970s, originally for:
 - Memory devices
 - Arithmetic data processing (computer chips)
- Usually made of Silicon ("Si")
 - \Rightarrow Has Same Light-Sensitive Properties as Silicon Light Meters

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CCDs have Revolutionized Astronomy

- Improved Light-Gathering Power of Telescopes by nearly 100×
 - Telescope w/ diameter of 150-mm (6") w/ CCD gets similar performance as 1960 Professional with 1-m (40") Telescope + Photographic Plates
- Now Considered to be "Standard" Sensor in Astronomical Imaging
 - Special Arrangements with Observatory Necessary to use Photographic Plates or Film

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Film/Plates Still Useful!!

- Large sizes can be made
 - ⇒ Large field of view
- Cheap!
- May be scanned to make digital images

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CCD

- Made from Crystalline Silicon (*Si*)
- Converts Photons of Light to Electronic Charges
 - Electrons
- Pattern of Light ⇒ Pattern of Charge ⇒ Image
- Electrons converted to current and read in sequence through amplifiers
 1. "Digitized"
 - Analog Measurements ("Voltages") Converted to Integer Values at Pixels
 2. "Digitized" Measurements Stored as Computer File

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Silicon Atoms

- 14 protons and electrons
 - Atomic "number" = 14
- 14 neutrons
 - Atomic "weight" = 14 + 14 = 28
- Discrete energy levels for electrons
 - ⇒ discrete set of transitions
 - ⇒ discrete spectrum



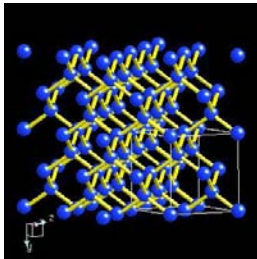
<http://www.webelements.com>

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Si Crystals

- Regular Pattern of Si atoms
 - Fixed Pattern of Spacings Between Atoms
- Atomic Structure Pattern
 - Forces "Perturb" Energy Levels and Changes Layout of Available Electron States



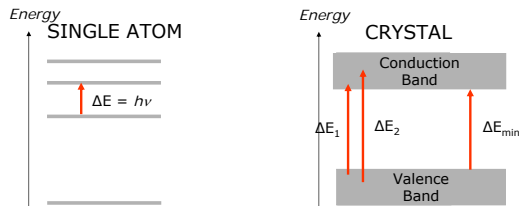
<http://www.webelements.com/webelements/elements/text/Si/xtal.html>

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Effect of Crystal Structure on Energy Levels

- Forces from Neighboring Atoms "Perturb" Electron Orbitals (Energy Levels)
 - Changes "Layout" of Energy Levels from Discrete States to Continuous "Bands"



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Electron States in *Si* Crystal

- Available States in Crystal Arranged in Discrete "Bands" of Energies
 - Lower Band \equiv *Valence Band*
 - ▶ More electrons
 - Upper Band \equiv *Conduction Band*
 - ▶ Fewer electrons, rove "free", can "conduct electricity"
- No States Exist in "Gap" Between Bands

The diagram shows two horizontal bars representing energy bands. The lower bar is labeled 'Valence Band of Electron States' and contains four small circles with minus signs (-). The upper bar is labeled 'Conduction Band of Electron States' and contains one such circle. Between the two bars is a vertical double-headed arrow labeled '"Gap"'. To the right of the gap, a bracket indicates 'Gap' \approx 1.11 electron-volts (eV). On the left, a vertical arrow points upwards and is labeled 'Increasing energy'.

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Action of Light on Electron States

- Incoming Photon with Energy Larger than the "Gap" of 1.11 eV
 - Absorbed and excites electrons from "Valence Band" to "Conduction Band"
- Electron in Conduction Band Roams through the Crystal "Lattice"
 - Not bound to any one atom
- Excited Electron e^- leaves "Hole" ("Lack of Electron" = h^+) in Valence Band
 - Hole = "Carrier" of Positive Charge

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Action of "Charge Carriers"

- Carriers are "Free" to Move in the Corresponding Band
 - Electron e^- moves freely in Conduction Band
 - Hole h^+ moves freely in Valence Band
- Charge carriers move as "current" when under influence of "voltage" force
 - Electrons are "counted" by measuring current
 - Current \propto Number of Electrons
 \propto Number of Absorbed Photons

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Wavelength λ corresponding to $E = 1.11$ electron Volts

- ⇒ Smallest measurable energy
- ⇒ Longest detectable wavelength of light
- $1 \text{ eV} = 1.602 \times 10^{-12} \text{ erg} = 1.602 \times 10^{-12} \text{ Joule}$

$$\lambda_{\max} = \frac{hc}{E_{\min}} = \frac{(6.624 \times 10^{-27} \text{ erg} \cdot \text{sec}) \cdot (3 \times 10^8 \frac{\text{m}}{\text{sec}})}{1.11 \text{ eV} \times (1.602 \times 10^{-12} \frac{\text{erg}}{\text{eV}})}$$
$$= 1.117 \times 10^{-6} \text{ m} = 1117 \text{ nm} = 1.12 \mu\text{m}$$

- ⇒ **To Energize Electron in Si Lattice Requires**
 $\lambda < 1.12 \mu\text{m}$, near-Infrared wavelength

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Energy and Wavelength

- If Wavelength of Incident Light is too long ($\lambda > 1.1 \mu\text{m}$), Photon CANNOT be Absorbed!
 - Insufficient Energy to "Kick" Electron from Valence Band to Conduction Band
- ⇒ Silicon is "Transparent" to long λ
- ⇒ CCDs constructed from Silicon are Insensitive to Long Wavelengths

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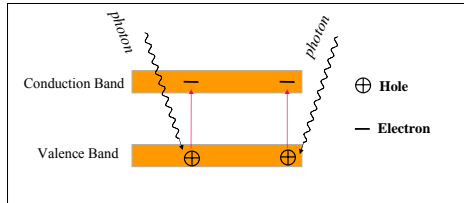
After Electron is Excited into Conduction Band...

- Electron and Hole Usually "Recombine" Quickly
 - Charge Carriers are "Lost"
- Prevent Recombination by Applying External Electric Field to "Separate" Electrons from Holes
 - Voltage attracts e^- toward positive terminal, h^+ toward negative terminal
- Field Attracts "Sweeps" Electrons and Holes in Opposite Directions:
 - ⇒ They don't recombine
 - Maintains Population of Charge Carriers
 - Allows Carriers to be "Counted"
 - ▶ Proportional to Incident Photons

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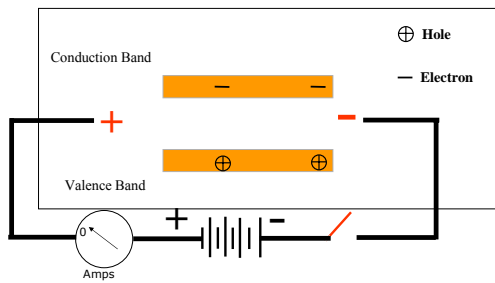
Generation of CCD Carriers



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Apply Voltage, Measure Current



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Thermal "Noise" in Measurement

- BUT: Other forms of energy have same effect as light
- **Thermally Generated Electrons** are *Indistinguishable* from photon-generated Electrons
 - Heat Energy can "Kick" e^- into Conduction Band
 - Thermal Electrons appear as "Noise" in Images
 - ▶ "Dark Current"
 - Keep CCDs **COLD** to Reduce Number of Thermally Generated Carriers (Dark Current)

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How to "Count" Charge Carriers ("Photoelectrons")?

- Must "Move" Charges (electrons and/or holes) to an "Amplifier"
- Professional CCDs: Amplifier Located at "Edge" of Light-Sensitive Region of CCD
 - Most of CCD Area "Sensitive" to Light
 - Charge Transfer is "Slow"
- CCDs in Video and Amateur Digital Cameras: Must Transfer Charge QUICKLY to take next shot
 - Less Sensor Area Available to Collect Light

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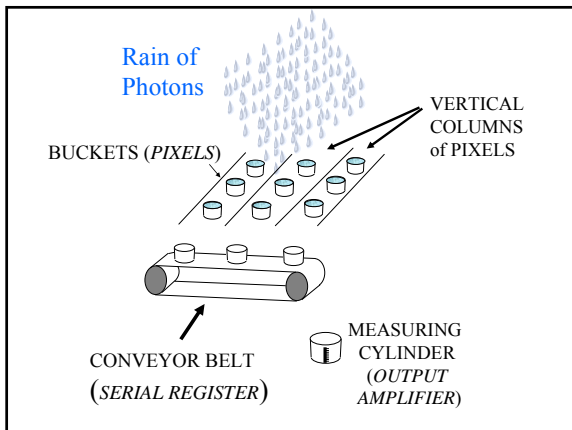
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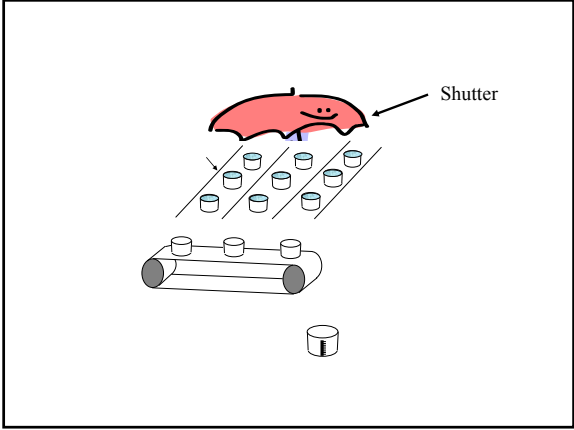
"Bucket Brigade" CCD Analogy

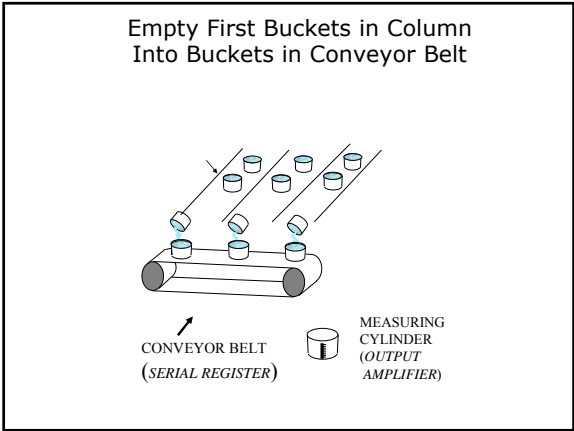
- Electron Charge Generated by Photons is "Transferred" from Pixel to "Edge" of Array
- Transferred Charges are "Counted" to Measure Number of Photons

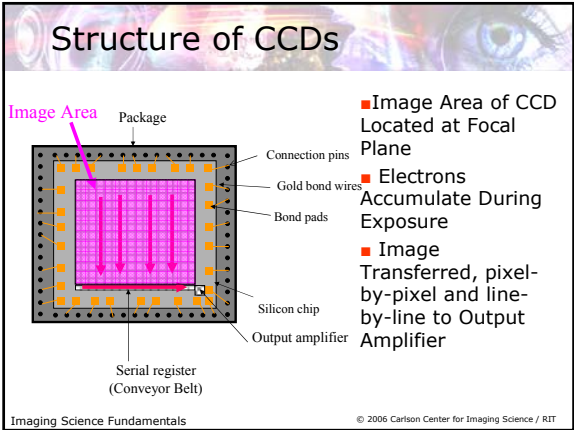
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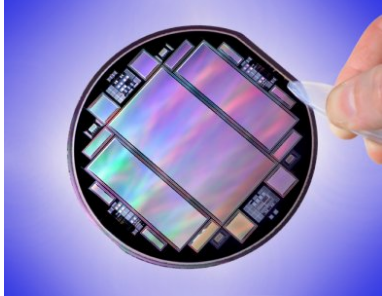








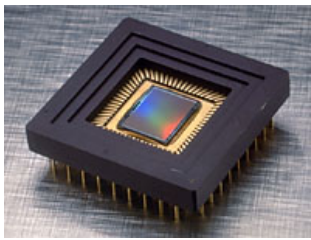
CCD Manufacture



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Don Groom LBNL
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Fabricated CCD



Kodak KAF1401 1317 × 1035 pixels (1,363,095 pixels)

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